

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S3	906	(702/57-59).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/19 14:41
S5	330	(702/81).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 15:00
S6	175	(702/82).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 16:01
S7	114	(702/83).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 16:07
S8	412	(702/84).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 16:23
S9	768	(702/89,108).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 16:25
S10	836	(702/117).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 16:28
S11	478	(702/118,119).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 16:30
S12	617	(702/120,121,123,125).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 16:41
S13	1281	(324/73.1).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/01/19 16:42
S14	225	(324/500,537,754,765).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:05
S16	234	(324/500,537,754,765).ccls. and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:07
S17	49	(438/14,16,17).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:05
S18	84	(438/14,16,17).ccls. and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:10

S19	144	(parametric and (test testing tested)).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:12
S20	1	(parametric and (test testing tested)).ti. and (load with wafer) same (automated or automatic\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:14
S23	106	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:25
S24	77	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with (controller controlling)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:30
S25	3	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:33
S26	0	parametric adj test\$3 and synchroniz\$3 with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:35
S27	0	parametric adj test\$3 and synchronization with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:41
S28	1	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near (data instrumentation instrument)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:50
S29	1	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:42
S30	1	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same load near test	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:42
S31	1	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near (data instrumentation instrument)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:42
S32	0	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:42
S33	2	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 17:42
S34	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:34

S35	1	parametric adj test\$3 and state adj oscillator	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:34
S37	1	state adj oscillator same fault-tolerant same test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:35
S38	1	state adj oscillator same fault-tolerant	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:35
S39	28	state adj oscillator same test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:42
S40	1	state adj oscillator same state near module	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:43
S41	0	state adj oscillator same state near object	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:43
S42	11	state adj oscillator same control adj state	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:45
S43	1	state adj oscillator same superstate	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:46
S44	79	superstate	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 18:46
S45	29	parametric adj test\$3 and (control controlling) adj state	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/01/19 19:02